
HD49335F/HF

CDS/PGA & 10-bit A/D TG Converter

REJ03F0100-0100Z

Rev.1.0

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Description

The HD49335F/HF is a CMOS IC that provides CDS-PGA analog processing (CDS/PGA) suitable for CCD camera digital signal processing systems together with a 10-bit A/D converter and timing generator in a single chip.

There are address map and timing generator charts besides this specification. May be contacted to our sales department if examining the details.

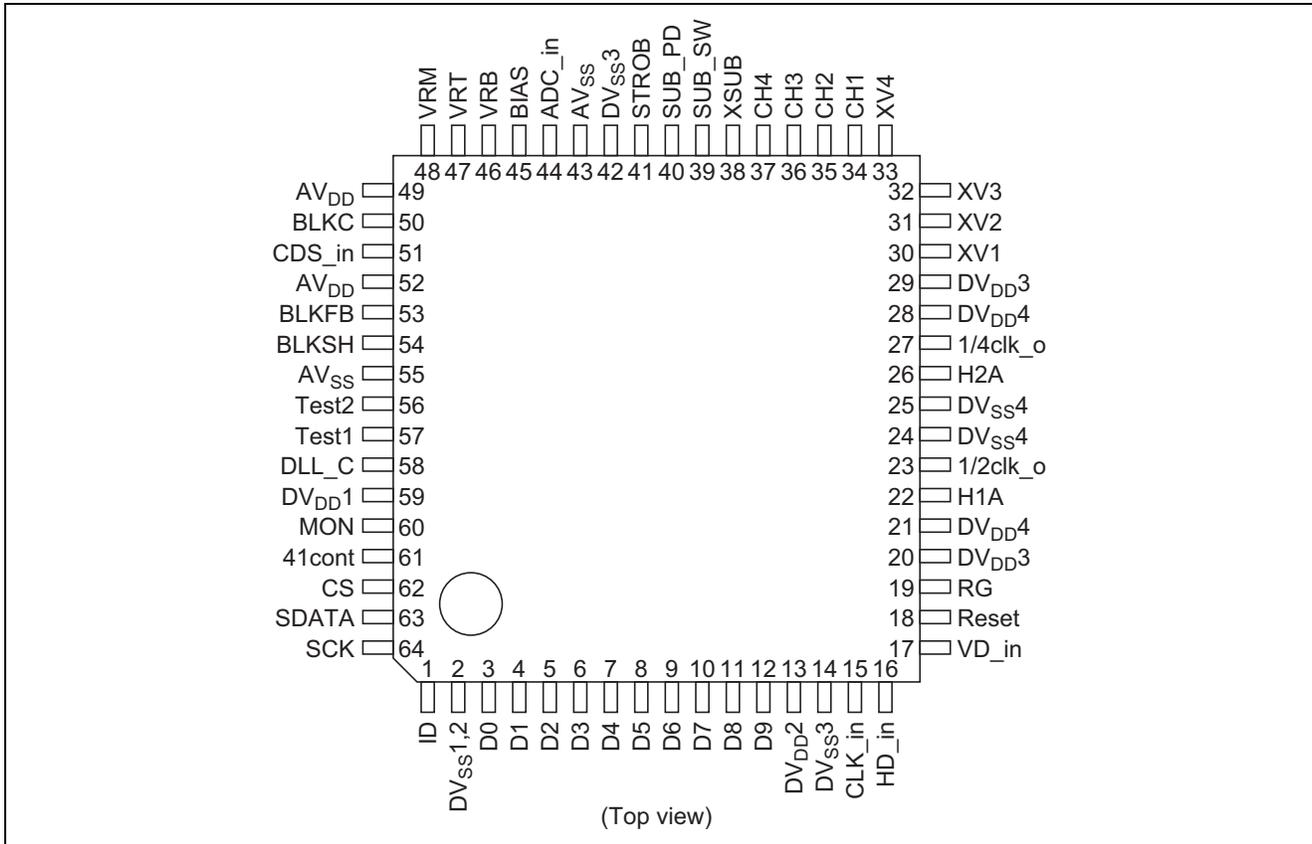
Functions

- Correlated double sampling
- PGA
- Serial interface control
- 10-bit ADC
- Timing generator
- Operates using only the 3 V voltage
- Corresponds to switching mode of power dissipation and operating frequency
Power dissipation: 220 mW (Typ), maximum frequency: 36 MHz (HD49335HF)
Power dissipation: 150 mW (Typ), maximum frequency: 25 MHz (HD49335F)
- ADC direct input mode
- QFP 64-pin package

Features

- Suppresses low-frequency noise, which output from CCD by the correlated double sampling.
- The S/H response frequency characteristics for the reference level can be adjusted using values of external parts and registers.
- High sensitivity is achieved due to the high S/N ratio and a wide dynamic range provided by a PG amplifier.
- PGA, pulse timing, standby mode, etc., is achieved via a serial interface.
- High precision is provided by a 10-bit-resolution A/D converter.
- Difference encoded gray code can be selected as an A/D output code. It is effective in suppression of solarization (wave pattern). It is patented by Renesas.
- Timing generator generates the all of pulse which are needed for CCD driving.

Pin Arrangement



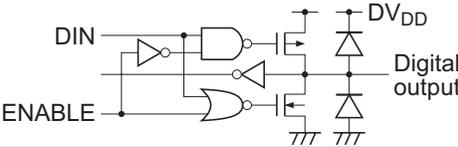
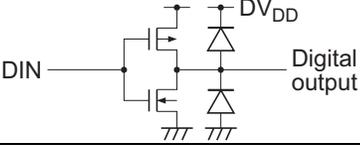
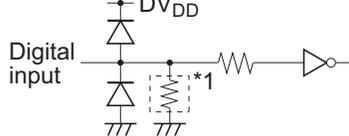
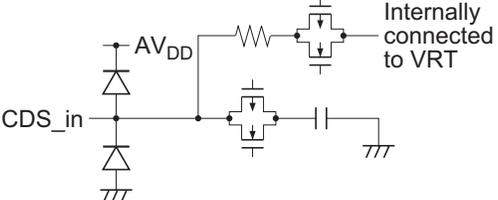
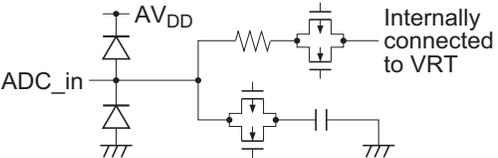
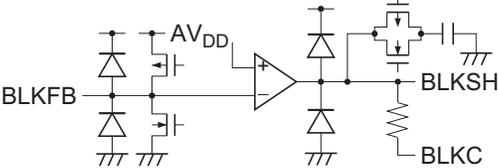
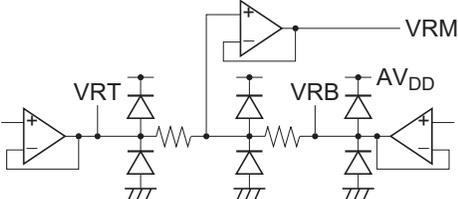
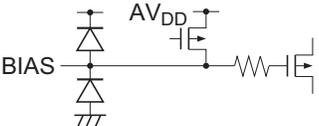
Pin Description

Pin No.	Symbol	Description	Analog(A) or		Remarks
			I/O	Digital(D)	
1	ID	Odd/even number line detecting pulse output pin	O	D	2 mA/10 pF
2	DV _{SS1,2}	CDS Digital ground + ADC output buffer ground (0 V)	—	D	
3 to 12	D0 to D9	Digital output (D0; LSB, D9; MSB)	O	D	2 mA/10 pF
13	DV _{DD2}	ADC output buffer power supply (3 V)	—	D	
14	DV _{SS3}	General ground for TG (0 V)	—	D	
15	CLK _{in}	CLK input (max 72 MHz)	I	D	
16	HD _{in}	HD input	I/O	D	
17	VD _{in}	VD input	I/O	D	
18	Reset	Hardware reset (for DLL reset)	I	D	Schmitt trigger
19	RG	Reset gate pulse output	O	D	3 mA/10 pF
20	DV _{DD3}	General power supply for TG (3 V)	—	D	
21	DV _{DD4}	H1 buffer power supply (3 V)	—	D	
22	H1A	H.CCD transfer pulse output-1A	O	D	30 mA/165 pF
23	1/2clk _o	CLK _{in} 2 divided output. 3 divided output at 3 divided mode	O	D	2 mA/10 pF
24	DV _{SS4}	H1 buffer ground (0 V)	—	D	
25	DV _{SS4}	H1 buffer ground (0 V)	—	D	
26	H2A	H.CCD transfer pulse output-2A	O	D	30 mA/165 pF
27	1/4clk _o	CLK _{in} 4 divided output. 6 divided output at 3 divided mode	O	D	2 mA/10 pF
28	DV _{DD4}	H2 buffer power supply (3 V)	—	D	
29	DV _{DD3}	General power supply for TG (3 V)	—	D	

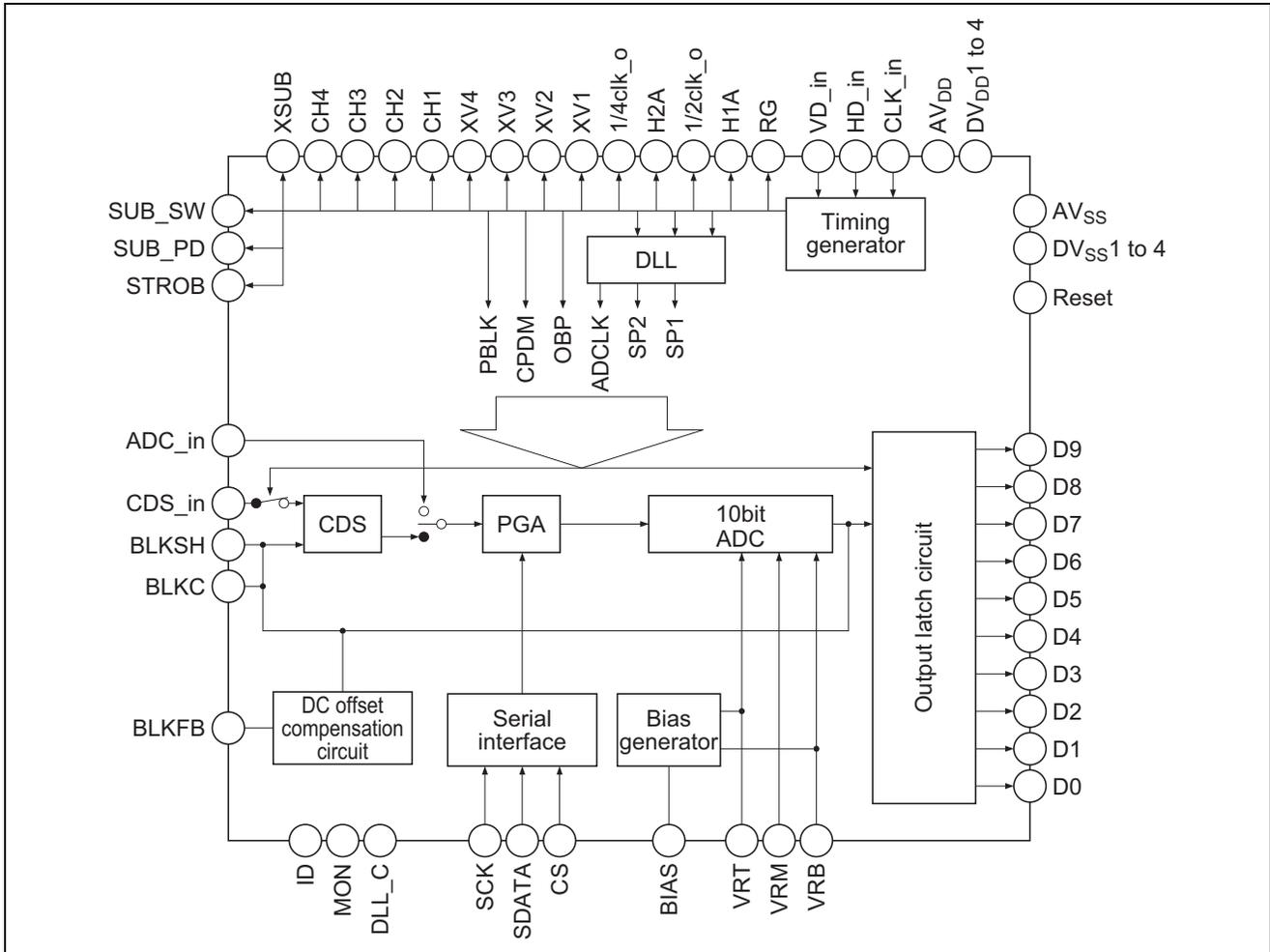
Pin Description (cont.)

Pin No.	Symbol	Description	I/O	Analog(A) or		Remarks
				Digital(D)		
30	XV1	V.CCD transfer pulse output-1	O	D		2 mA/10 pF
31	XV2	V.CCD transfer pulse output-2	O	D		2 mA/10 pF
32	XV3	V.CCD transfer pulse output-3	O	D		2 mA/10 pF
33	XV4	V.CCD transfer pulse output-4	O	D		2 mA/10 pF
34	CH1	Read out pulse output-1	O	D		2 mA/10 pF
35	CH2	Read out pulse output-2	O	D		2 mA/10 pF
36	CH3	Read out pulse output-3	O	D		2 mA/10 pF
37	CH4	Read out pulse output-4/XV6 at stripe mode	O	D		2 mA/10 pF
38	XSUB	Pulse output for electronic shutter	O	D		2 mA/10 pF
39	SUB_SW	SUB voltage control output-1. ADCK input	I/O	D		2 mA/10 pF
40	SUB_PD	SUB voltage control output-2/ XV5 at stripe mode	O	D		2 mA/10 pF
41	STROB	Flash control output. Input Vgate at Hi of pin 61	I/O	D		2 mA/10 pF
42	DV _{SS3}	General ground for TG (0 V)	—	D		
43	AV _{SS}	Analog ground (0 V)	—	A		
44	ADC_in	AD converter input pin	I	A		
45	BIAS	Bias standard resistance	—	A		
46	VRB	ADC bottom standard voltage (0.1 μ F for GND)	—	A		
47	VRT	ADC top standard voltage (0.1 μ F for GND)	—	A		
48	VRM	ADC middle standard voltage (0.1 μ F for GND)	—	A		
49	AV _{DD}	Analog power supply (3 V)	—	A		
50	BLKC	Black level C pin (1000 pF for GND)	—	A		
51	CDS_in	CDS input pin	I	A		
52	AV _{DD}	Analog power supply (3 V)	—	A		
53	BLKFB	Black level FB pin (1 μ F between BLKFB and BLKSH)	I	A		
54	BLKSH	Black level S/H pin	O	A		
55	AV _{SS}	Analog ground (0 V)	—	A		
56	Test2	H: Normal operation, L: CDS single operation mode Input 36; PBLK at testing, Input 37; OBP, Input 38; CPDM, Input 39; ADCK, Input 40; SP2, Input 41; SP1	I	D		
57	Test1	L: Slave mode, H: Master mode	I	D		
58	DLL_C	Analog delay DLL external C pin (100 pF for GND)	O	A		
59	DV _{DD1}	Digital power supply (3 V) CDS, PAG, ADC part	—	D		
60	MON	Pulse monitor (SP1, SP2, ADCK, OBP, CPDM, PBLK input)	O	D		2 mA/10 pF
61	41cont	Input STROB = pin 41, Input SUB_SW = pin 39 at Low Input Vgate = pin 41, Input ADCK = pin 39 at Hi	I	D		
62	CS	Serial data CS at CDS part	I	D		
63	SDATA	Input serial data	I	D		
64	SCK	Input serial clock	I	D		

Input/Output Equivalent Circuit

Pin Name	Equivalent Circuit
Digital output	<p>D0 to D9, HD_in, VD_in, H1A, H2A, 1/2clk_o, 1/4clk_o, 41cont, SUB_SW, SUB_PD</p>  <p>DIN</p> <p>ENABLE</p> <p>DV_{DD}</p> <p>Digital output</p>
	<p>ID, RG, MON, XV1 to XV4, CH1 to CH4, XSUB</p>  <p>DIN</p> <p>DV_{DD}</p> <p>Digital output</p>
Digital input	<p>CLK_in, HD_in, VD_in, ADCLK, OBP, SPBLK, SPSIG, CS, SCK, SDATA, PBLK, OEB, Reset, Test1, Test2, SUB_SW, STROB</p>  <p>DV_{DD}</p> <p>Digital input</p> <p>Note: Only OEB is pulled down to about 70 kΩ.</p>
Analog	<p>CDS_in</p>  <p>AV_{DD}</p> <p>CDS_in</p> <p>Internally connected to VRT</p>
	<p>ADC_in</p>  <p>AV_{DD}</p> <p>ADC_in</p> <p>Internally connected to VRT</p>
	<p>BLKSH, BLKFB, BLKC</p>  <p>AV_{DD}</p> <p>BLKFB</p> <p>BLKSH</p> <p>BLKC</p>
	<p>VRT, VRM, VRB</p>  <p>AV_{DD}</p> <p>VRT</p> <p>VRB</p> <p>VRM</p>
	<p>BIAS</p>  <p>AV_{DD}</p> <p>BIAS</p>

Block Diagram



Internal Functions

Functional Description

- CDS input
 - CCD low-frequency noise is suppressed by CDS (correlated double sampling).
 - The signal level is clamped at 14 LSB to 76 LSB by resistor during the OB period. *¹
 - Gain can be adjusted using 8 bits of register (0.132 dB steps) within the range from -2.36 dB to 31.40 dB. *²
- ADC input
 - The center level of the input signal is clamped at 512 LSB (Typ).
 - Gain can be adjusted using 8 bits of register (0.01784 times steps, register settings) within the range from 0.57 times (-4.86 dB) to 5.14 times (14.22 dB). *²
- Automatic offset calibration of PGA and ADC
- DC offset compensation feedback for CCD and CDS
- Pre-blanking
 - Digital output is fixed at clamp level
- Digital outputs enable function

Note: 1. It is not covered by warranty when 14LSB settings
 2. Full-scale digital output is defined as 0 dB (one time) when 1 V is input.

Operating Description

Figure 1 shows CDS/PGA + ADC function block.

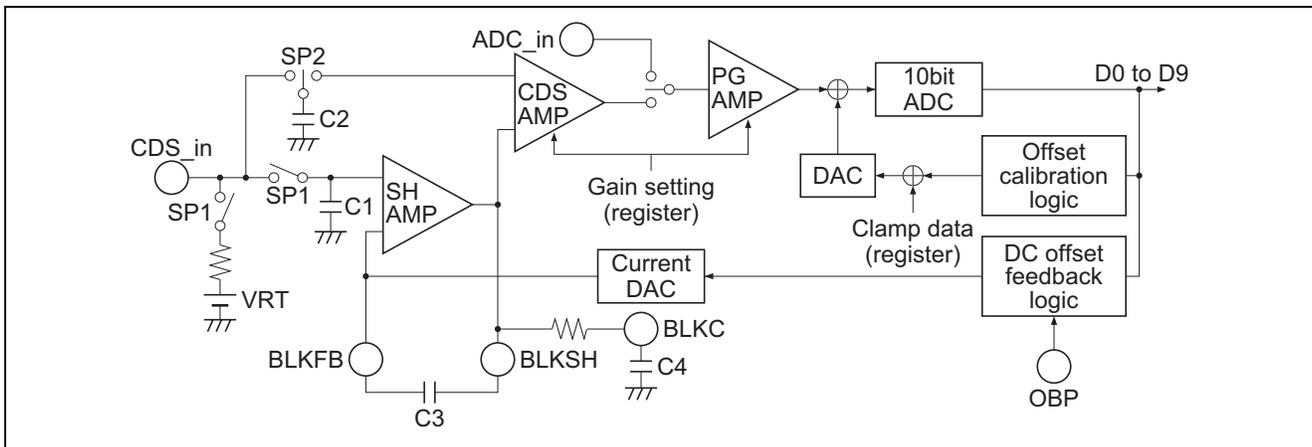


Figure 1 CDS/PGA Functional Block Diagram

1. CDS (Correlated Double Sampling) Circuit

The CDS circuit extracts the voltage differential between the black level and a signal including the black level. The black level is directly sampled at C1 by using the SP1 pulse, buffered by the SHAMP, then provided to the CDSAMP.

The signal level is directly sampled at C2 by using the SP2 pulse, and then provided to CDSAMP (see figure 1). The difference between these two signal levels is extracted by the CDSAMP, which also operates as a programmable gain amplifier at the previous stage. The CDS input is biased with VRT (2 V). During the PBLK period, the above sampling and bias operation are paused.

2. PGA Circuit

The PGAMP is the programmable gain amplifier for the latter stage. The PGAMP and the CDSAMP set the gain using 8 bits of register.

The equation below shows how the gain changes when register value N is from 0 to 255.

In CDSIN mode: Gain = (-2.36 dB + 0.033 dB) × N (LOG linear).

In ADCIN mode: Gain = (0.57 times + 0.001784 times) × N (linear).

Full-scale digital output is defined as 0 dB (one time) when 1 V is input.

3. Automatic Offset Calibration Function and Black-Level Clamp Data Settings

The DAC DC voltage added to the output of the PGA amplifier is adjusted by automatic offset calibration.

The data, which cancels the output offset of the PGA amplifier and the input offset of the ADC, and the clamp data (14 LSB to 76 LSB) set by register are added and input to the DAC.

The automatic offset calibration starts automatically after the RESET mode set by register is cancelled and terminates after 40000 clock cycles (when fclk = 20 MHz, 2 ms).

4. DC Offset Compensation Feedback Function

Feedback is done to set the black signal level input during the OB period to the DC standard, and all offsets (including the CCD offset and the CDSAMP offset) are compensated for.

The offset from the ADC output is calculated during the OB period, and SHAMP feedback capacitor C3 is charged by the current DAC (see figure 1).

The open-loop differential gain ($\Delta\text{Gain}/\Delta\text{H}$) per 1 H of the feedback loop is given by the following equation. 1H is the one cycle of the OBP.

$$\Delta\text{Gain}/\Delta\text{H} = 0.078/(\text{fclk} \times \text{C3}) \quad (\text{fclk: ADCLK frequency, C3: SHAMP external feedback capacitor})$$

Example: When fclk = 20 MHz and C3 = 1.0 μF , $\Delta\text{Gain}/\Delta\text{H} = 0.0039$

When the PGAMP gain setting is changed, the high-speed lead-in operation state is entered, and the feedback loop gain is increased by a multiple of N. Loop gain multiplication factor N can be selected from 2 times, 4 times, 8 times, or 16 times by changing the register settings (see table 1). Note that the open-loop differential gain ($\Delta\text{Gain}/\Delta\text{H}$) must be one or lower. If it is two or more, oscillation occurs.

The time from the termination of high-speed lead-in operation to the return of normal loop gain operation can be selected from 1 H, 2 H, 4 H, or 8 H. If the offset error is over 16 LSB, the high-speed lead-in operation continues, and when the offset error is 16 LSB or less, the operation returns to the normal loop-gain operation after 1 H, 2 H, 4 H, or 8 H depending on the register settings. (Refer to table 2.)

Table 1 Loop Gain Multiplication Factor during High-Speed Lead-In Operation

HGain-Nsel (register settings)		Multiplication Factor N
[0]	[1]	
L	L	4
H	L	8
L	H	16
H	H	32

Table 2 High-Speed Lead-In Operation Cancellation Time

HGstop-Hsel (register settings)		Cancellation Time
[0]	[1]	
L	L	1 H
H	L	2 H
L	H	4 H
H	H	8 H

5. Pre-Blanking Function

During the PBLK input period, the CSD input operation is separated and protected from the large input signal. The ADC digital output is fixed to clamp data (14 to 76 LSB).

6. ADC Digital Output Control Function

The ADC digital output includes the functions output enable, code conversion, and test mode. Tables 3, 4 and 5 show the output functions and the codes.

Table 3 ADC Digital Output Functions

STBY	TEST0	TEST1	LINV	MINV	PBLK	ADC Digital Output										Operating Mode			
						D9	D8	D7	D6	D5	D4	D3	D2	D1	D0				
H	X	X	X	X	X	Hi-Z											Low-power wait state		
L	L	L	L	L	L	Same as in table 4.											Normal operation		
			L	H	L	D9 is inverted in table 4.													
			H	L	L	D8 to D0 are inverted in table 4.													
			H	H	L	D9 to D0 are inverted in table 4.													
			X	X	H	Output code is set up to Clamp Level.													
			X	X	H	Output code is set up to Clamp Level.													
	L	H	H	L	L	L	Same as in table 5.											Normal operation	
				L	H	L	D9 is inverted in table 5.												
				H	L	L	D8 to D0 are inverted in table 5.												
				H	H	L	D9 to D0 are inverted in table 5.												
				X	X	H	Output code is set up to Clamp Level.												
				X	X	H	Output code is set up to Clamp Level.												
L	H	X	L	L	X		H	L	H	L	H	L	H	L	H	L	Test mode		
			L	H	X		L	L	H	L	H	L	H	L	H	L			
			H	L	X		H	H	L	H	L	H	L	H	L	H			
			H	H	X		L	H	L	H	L	H	L	H	L	H			

Note: 1. STBY, TEST, LINV, and MINV are set by register.

Table 4 ADC Output Code (Binary)

Output Pin			D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	
Output codes	Steps	3	L	L	L	L	L	L	L	L	H	H	
		4	L	L	L	L	L	L	L	L	H	L	L
		5	L	L	L	L	L	L	L	L	H	L	H
		6	L	L	L	L	L	L	L	L	H	H	L
	
		511	L	H	H	H	H	H	H	H	H	H	H
		512	H	L	L	L	L	L	L	L	L	L	L
	
		1020	H	H	H	H	H	H	H	H	H	L	L
		1021	H	H	H	H	H	H	H	H	H	L	H
		1022	H	H	H	H	H	H	H	H	H	H	L
		1023	H	H	H	H	H	H	H	H	H	H	H

Table 5 ADC Output Code (Gray)

Output Pin			D9	D8	D7	D6	D5	D4	D3	D2	D1	D0	
Output codes	Steps	3	L	L	L	L	L	L	L	L	H	L	
		4	L	L	L	L	L	L	L	L	H	H	L
		5	L	L	L	L	L	L	L	L	H	H	H
		6	L	L	L	L	L	L	L	L	H	L	H
	
		511	L	H	L	L	L	L	L	L	L	L	L
		512	H	H	L	L	L	L	L	L	L	L	L
	
		1020	H	L	L	L	L	L	L	L	L	H	L
		1021	H	L	L	L	L	L	L	L	L	H	H
		1022	H	L	L	L	L	L	L	L	L	L	H
		1023	H	L	L	L	L	L	L	L	L	L	L

7. Adjustment of Black-Level S/H Response Frequency Characteristics

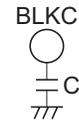
The CR time constant that is used for sampling/hold (S/H) at the black level can be adjusted by changing the register settings, as shown in table 6.

Table 6 SHSW CR Time Constant Setting

	SHSW-fsel (Register setting)																															
	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]				
	L	L	L	L	H	L	L	L	L	H	L	L	H	H	L	L	L	L	H	L	H	L	H	L	L	H	H	L	H	H	H	L
CR Time Constant (Typ) (cutoff frequency conversion)	2.20 nsec (72 MHz)				2.30 nsec (69 MHz)				2.51 nsec (63 MHz)				2.64 nsec (60 MHz)				2.93 nsec (54 MHz)				3.11 nsec (51 MHz)				3.52 nsec (45 MHz)				3.77 nsec (42 MHz)			

	SHSW-fsel (Register setting)																															
	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]	[0]	[1]	[2]	[3]				
	L	L	L	H	H	L	L	H	L	H	L	H	H	H	L	H	L	L	H	H	H	L	H	H	L	H	H	H	H	H	H	H
CR Time Constant (Typ) (cutoff frequency conversion)	4.40 nsec (36 MHz)				4.80 nsec (33 MHz)				5.87 nsec (27 MHz)				6.60 nsec (24 MHz)				8.80 nsec (18 MHz)				10.6 nsec (15 MHz)				17.6 nsec (9 MHz)				26.4 nsec (6 MHz)			

8. The SHAMP frequency characteristics can be adjusted by changing the register settings and the C4 value of the external pin. The settings are shown in table 7. Values other than those shown in the table 7 cannot be used.



Recommendation value of C is 1000 pF

Table 7 SHAMP Frequency Characteristics Setting

LoPwr (Register setting)	SHA-fsel (Register setting)							
	[0]	[1]	[0]	[1]	[0]	[1]	[0]	[1]
	L	L	H	L	L	H	H	H
"Lo"	230 MHz 6800 pF (240 pF)		116 MHz 10000 pF (270 pF)		75 MHz 13000 pF (300 pF)		56 MHz 18000 pF (360 pF)	
"Hi"	100 MHz 10000 pF (560 pF)		49 MHz 15000 pF (620 pF)		32 MHz 22000 pF (750 pF)		24 MHz 27000 pF (820 pF)	

Note: Upper line : SHAMP cutoff frequency (Typ)
 Middle line : Standard value of C4 (maximum value is not defined)
 Lower line : Minimum value of C4 (do not set below this value)

Timing Chart

Figure 2 shows the timing chart when CDSIN and ADCIN input modes are used.

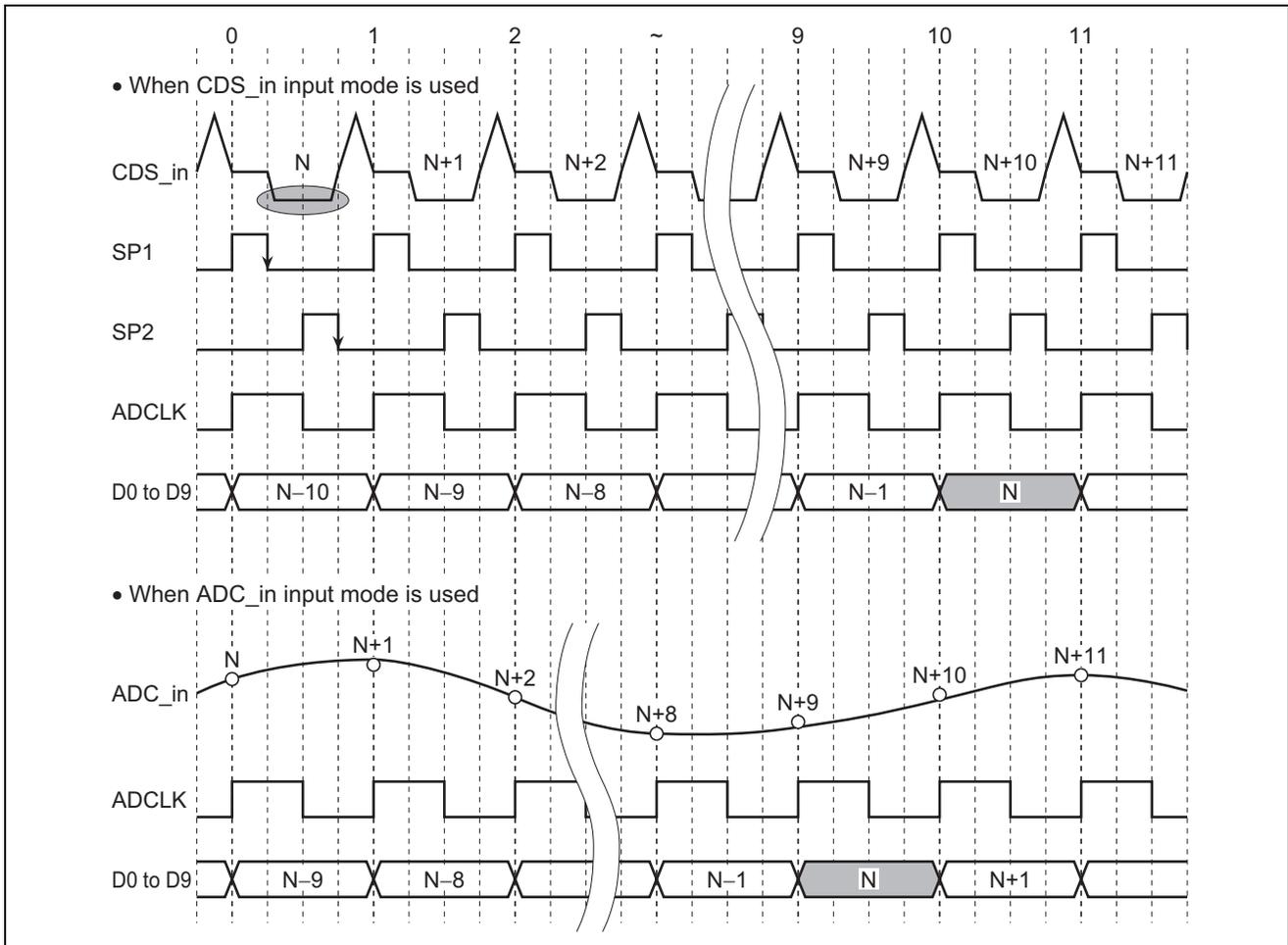


Figure 2 Output Timing Chart when CDSIN and ADCIN Input Modes are Used

- The ADC output (D0 to D9) is output at the rising edge of the ADCLK in both modes.
- Pipe-line delay is ten clock cycles when CDSIN is used and nine when ADCIN is used.
- In ADCIN input mode, the input signal is sampled at the rising edge of the ADCLK.

Detailed Timing Specifications

Detailed Timing Specifications when CDSIN Input Mode is Used

Figure 3 shows the detailed timing specifications when the CDSIN input mode is used, and table 8 shows each timing specification.

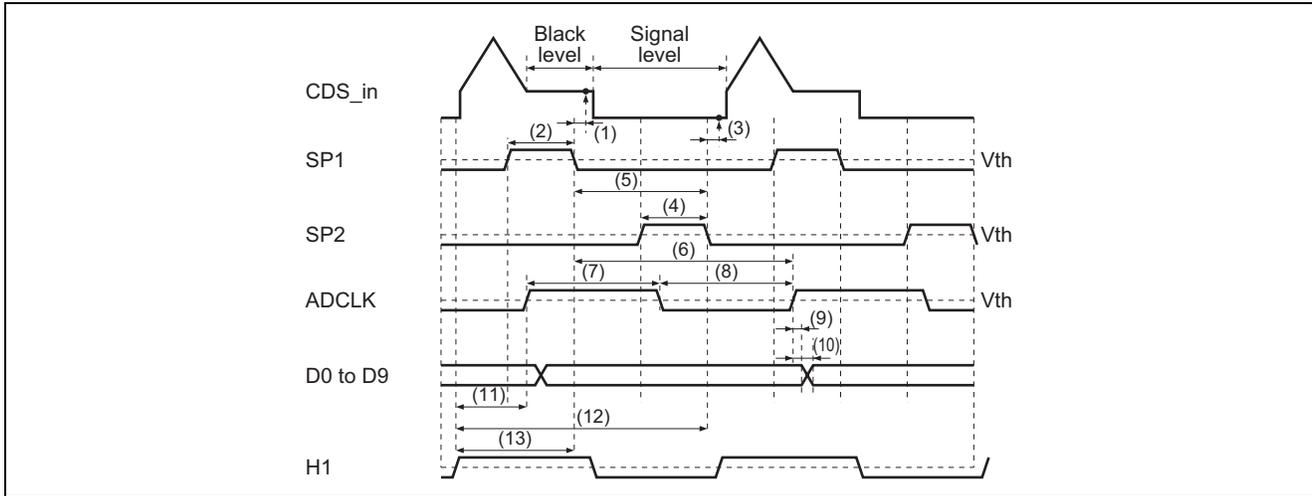


Figure 3 Detailed Timing Chart when CDSIN Input Mode is Used

Table 8 Timing Specifications when the CDSIN Input Mode is Used

No.	Timing	Symbol	Min	Typ	Max	Unit
(1)	Black-level signal fetch time	t_{CDS1}	—	(1.5)	—	ns
(2)	SP1 'Hi' period	t_{CDS2}	$Typ \times 0.8$	$1/4f_{CLK}$	$Typ \times 1.2$	ns
(3)	Signal-level fetch time	t_{CDS3}	—	(1.5)	—	ns
(4)	SP2 'Hi' period	t_{CDS4}	$Typ \times 0.8$	$1/4f_{CLK}$	$Typ \times 1.2$	ns
(5)	SP1 falling to SP2 falling time	t_{CDS5}	$Typ \times 0.85$	$1/2f_{CLK}$	$Typ \times 1.15$	ns
(6)	SP1 falling to ADCLK rising inhibit time	t_{CDS6}	—	(5)	—	ns
(7), (8)	ADCLK $t_{WH} \text{ min.}/t_{WL} \text{ min}$	$t_{CDS7,8}$	11	—	—	ns
(9)	ADCLK rising to digital output holding time	t_{CHLD9}	—	(7)	—	ns
(10)	ADCLK rising to digital output delay time	t_{COD10}	—	(16)	—	ns
(11)	H1 rising to ADCLK rising time	t_{CDS11}	—	$(1/4f_{CLK})$	—	ns
(12)	H1 rising to SPSIG falling time	t_{CDS12}	—	$(1/f_{CLK})$	—	ns
(13)	H1 rising to SPBLK falling time	t_{CDS13}	—	$(1/2f_{CLK})$	—	ns

OBP Detailed Timing Specifications

Figure 4 shows the OBP detailed timing specifications.

The OB period is from the fifth to the twelfth clock cycle after the OB pulse is inputted. The average of the black signal level is taken for eight input cycles during the OB period and it becomes the clamp level (DC standard).

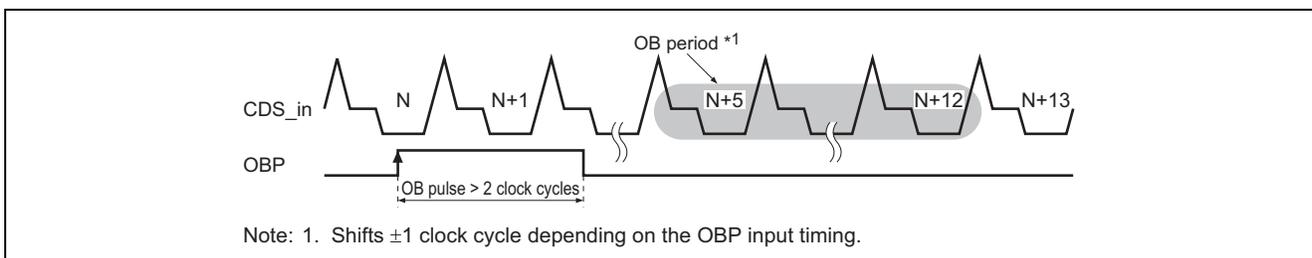


Figure 4 OBP Detailed Timing Specifications

Detailed Timing Specifications at Pre-Blanking

Figure 5 shows the pre-blanking detailed timing specifications.

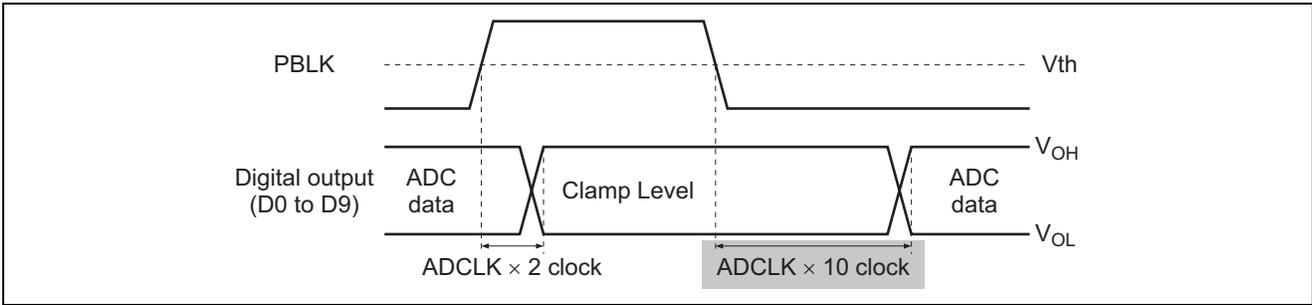


Figure 5 Detailed Timing Specifications at Pre-Blanking

Detailed Timing Specifications when ADCIN Input Mode is Used

Figure 6 shows the detailed timing chart when ADCIN input mode is used, and table 9 shows each timing specification.

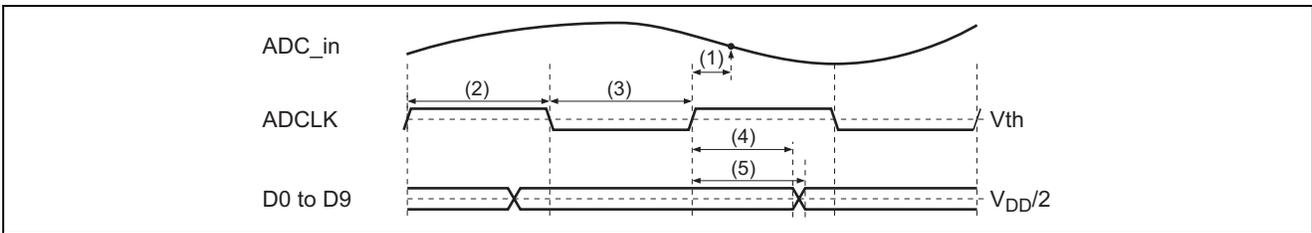


Figure 6 Detailed Timing Chart when ADCIN Input Mode is Used

Table 9 Timing Specifications when ADCIN Input Mode is Used

No.	Timing	Symbol	Min	Typ	Max	Unit
(1)	Signal fetch time	t_{ADC1}	—	(6)	—	ns
(2), (3)	ADCLK t_{WH} min./ t_{WL} min.	$t_{ADC2,3}$	$Typ \times 0.85$	$1/2f_{ADCLK}$	$Typ \times 1.15$	ns
(4)	ADCLK rising to digital output hold time	t_{AHL4}	—	(14.5)	—	ns
(5)	ADCLK rising to digital output delay time	t_{AOD5}	—	(23.5)	—	ns

Dummy Clamp

It adjusts the mis-clamp which occurs when taking the photo under the highlight conditions. (Like a sun) Normally it works with the OB clamp, however when black level is out of the range caused by highlight enter to OB part, it changes to clamp processing by dummy bit level. Resister settings are follows.

D12, D11, D10 of address H'F7 (Dummy CP)
 0, 0, 0 ; OFF
 0, 0, 1 ; +32
 0, 1, 0 ; +64
 0, 1, 1 ; +96
 :
 :
 1, 1, 1 ; +224

D8, D8 of address H'F7 (DMCG)
 The amount of feed back current can be reduced with only dummy clamp.
 Data = 0:1/4
 1:1/8
 2:1/16
 3:1/32

The amount of offset are changes automatically depends on PGA gain in the LSI.

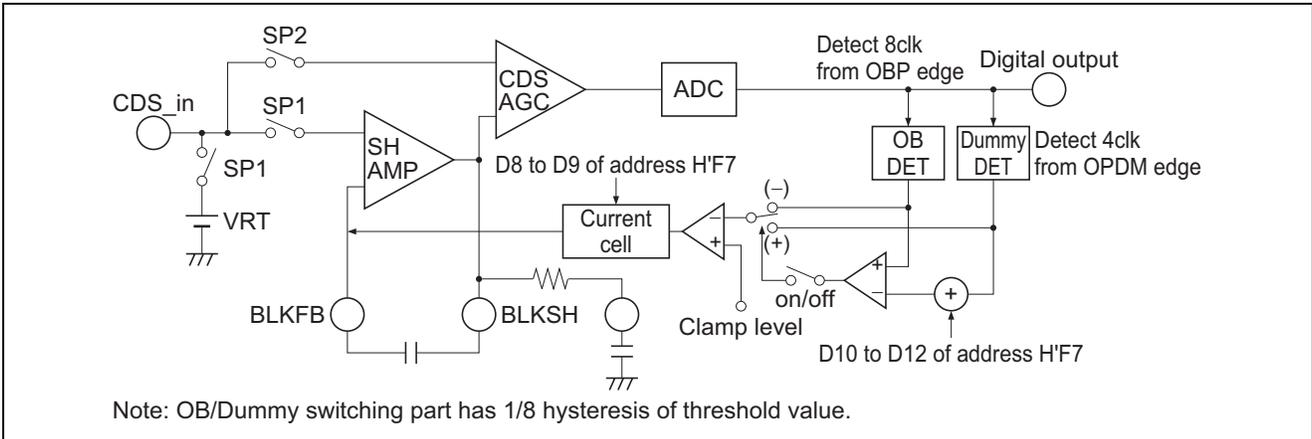


Figure 7 Internal Bias Circuitry

Absolute Maximum Ratings

(Ta = 25°C)

Item	Symbol	Ratings	Unit
Power supply voltage	V _{DD}	4.1	V
Analog input voltage	V _{IN}	-0.3 to AV _{DD} +0.3	V
Digital input voltage	V _I	-0.3 to DV _{DD} +0.3	V
Operating temperature range	Ta	-20 to +85	°C
Power dissipation	Pt	590	mW
Storage temperature	Tstg	-55 to +125	°C
Power supply voltage	Vopr	2.70 to 3.30	V

Note: AV_{DD}, AV_{SS} are analog power source systems of CDS, PGA, and ADC.

DV_{DD1}, DV_{SS1} are digital power source systems of CDS, PGA and ADC.

DV_{DD2}, DV_{SS2} are buffer power source systems of ADC output.

DV_{DD3}, DV_{SS3} are general digital power source systems of TG.

DV_{DD4}, DV_{SS4} are buffer power source systems of H1 and H2.

- Pin 2 multi bonds the DV_{SS1} and DV_{SS2}

- When pin 64 is set to Low, pin 41 = STROB output, pin 39 = SUB_SW output

When Hi, pin 41 = Vgate input, pin 39 = ADCK input

Electrical Characteristics

(Unless othewide specified, Ta = 25°C, AV_{DD} = 3.0 V, DV_{DD} = 3.0 V, and R_{BIAS} = 33 kΩ)

- Items Common to CDSIN and ADCIN Input Modes

Item	Symbol	Min	Typ	Max	Unit	Test Conditions	Remarks
Power supply voltage range	V _{DD}	2.70	3.00	3.30	V		
Conversion frequency	f _{CLK hi}	20	—	36	MHz	LoPwr = low *2	HD49335HF
	f _{CLK low}	5.5	—	25	MHz	LoPwr = high *2	HD49335F
Digital input voltage	V _{IH2}	$2.25 \times \frac{DV_{DD}}{3.0}$	—	DV _{DD}	V		CS, SCK, SDATA
	V _{IL2}	0	—	$0.6 \times \frac{DV_{DD}}{3.0}$	V		
Digital output voltage	V _{OH}	DV _{DD} -0.5	—	—	V	I _{OH} = -1 mA	
	V _{OL}	—	—	0.5	V	I _{OL} = +1 mA	
Digital input current	I _{IH}	—	—	50	μA	V _{IH} = 3.0 V	
	I _{IL}	-50	—	—	μA	V _{IL} = 0 V	
ADC resolution	RES	10	10	10	bit		
ADC integral linearity	INL	—	(2)	—	LSBp-p	f _{CLK} = 25 MHz	
ADC differential linearity+	DNL+	—	0.3	0.99	LSB	f _{CLK} = 25 MHz	*1
ADC differential linearity-	DNL-	-0.99	-0.3	—	LSB	f _{CLK} = 25 MHz	*1
Sleep current	I _{SLP}	-100	0	100	μA	Digital input pin is set to 0 V, output pin is open	
Standby current	I _{STBY}	—	3	5	mA	Digital I/O pin is set to 0 V	

Notes: 1. Differential linearity is the calculated difference in linearity errors between adjacent codes.

2. 2 divided mode: f_{CLK} = 1/2CLK_{in}

3 divided mode: f_{CLK} = 1/3CLK_{in}

3. Values within parentheses () are for reference.

Electrical Characteristics (cont.)

(Unless othewide specified, Ta = 25°C, AV_{DD} = 3.0 V, DV_{DD} = 3.0 V, and R_{BIAS} = 33 kΩ)

• Items for CDSIN Input Mode

Item	Symbol	Min	Typ	Max	Unit	Test Conditions	Remarks
Consumption current (1)	I _{DD1}	—	84	96.6	mA	f _{CLK} = 36 MHz	CDSIN mode LoPwr = low
Consumption current (2)	I _{DD2}	—	58	66.7	mA	f _{CLK} = 20 MHz	CDSIN mode LoPwr = high
CCD offset tolerance range	V _{CCD}	(-100)	—	(100)	mV		
Timing specifications (1)	t _{CDS1}	—	(1.5)	—	ns		Refer to table 8
Timing specifications (2)	t _{CDS2}	Typ × 0.8	1/4f _{CLK}	Typ × 1.2	ns		
Timing specifications (3)	t _{CDS3}	—	(1.5)	—	ns		
Timing specifications (4)	t _{CDS4}	Typ × 0.8	1/4f _{CLK}	Typ × 1.2	ns		
Timing specifications (5)	t _{CDS5}	Typ × 0.85	1/2f _{CLK}	Typ × 1.15	ns		
Timing specifications (6)	t _{CDS6}	1	5	9	ns		
Timing specifications (7)	t _{CDS7}	—	1/2f _{CLK}	—	ns		
Timing specifications (8)	t _{CDS8}	—	1/2f _{CLK}	—	ns		
Timing specifications (9)	t _{CHLD9}	—	(7)	—	ns	C _L = 10 pF	
Timing specifications (10)	t _{COD10}	—	(16)	—	ns	C _L = 10 pF	
Timing specifications (11)	t _{CDS11}	—	(1/4f _{CLK})	—	ns		
Timing specifications (12)	t _{CDS12}	—	(1/f _{CLK})	—	ns		
Timing specifications (13)	t _{CDS13}	—	(1/2f _{CLK})	—	ns		
Clamp level	CLP(00)	—	(14)	—	LSB		
	CLP(09)	—	(32)	—	LSB		
	CLP(31)	—	(76)	—	LSB		
PGA gain at CDS input	AGC(0)	-4.4	-2.4	-0.4	dB		*1
	AGC(63)	4.1	6.1	8.1	dB		
	AGC(127)	12.5	14.5	16.5	dB		
	AGC(191)	21.0	23.0	25.0	dB		
	AGC(255)	29.4	31.4	33.4	dB		
DLL operation frequency	DLL_2	11	—	25	MHz		*2
	DLL_3	7	—	11	MHz		*3
	DLL_4	5.5	—	7	MHz		*4
T/G 3/1 divided operation frequency range	CLK_in3	28.6	—	28.6	MHz	f _{CLK} = 1/3CLK_in3	
H Buffer output voltage	V _{OH}	2.94	2.97	—	V	30 mA Buff, I _{OH} = -5 mA	
	V _{OL}	—	22	47	MV	30 mA Buff, I _{OL} = +5 mA	
	V _{OH}	2.89	2.94	—	V	14 mA Buff, I _{OH} = -5 mA	
	V _{OL}	—	50	112	MV	14 mA Buff, I _{OL} = +5 mA	
	V _{OH}	2.91	2.96	—	V	10 mA Buff, I _{OH} = -3 mA	
	V _{OL}	—	36	78	MV	10 mA Buff, I _{OL} = +3 mA	
	V _{OH}	2.85	2.93	—	V	4 mA Buff, I _{OH} = -2 mA	
	V _{OL}	—	60	129	MV	4 mA Buff, I _{OL} = +2 mA	
	V _{OH}	2.69	2.86	—	V	2 mA Buff, I _{OH} = -2 mA	
V _{OL}	—	115	262	mV	2 mA Buff, I _{OL} = +2 mA		
RG output voltage	V _{OH}	2.81	2.90	—	V	I _{OH} = -2 mA	
	V _{OL}	—	78	141	mV	I _{OL} = +2 mA	

- Notes: 1. Define digital output full scall with 1 V input as 0 dB.
 2. Number of master steps: 60 steps, DLL current High
 3. Number of master steps: 40 steps, DLL current Low
 4. Number of master steps: 60 steps, DLL current Low
 5. Values within parentheses () are for reference.

Electrical Characteristics (cont.)

(Unless othewide specified, Ta = 25°C, AV_{DD} = 3.0 V, DV_{DD} = 3.0 V, and R_{BIAS} = 33 kΩ)

• Items for ADCIN Input Mode

Item	Symbol	Min	Typ	Max	Unit	Test Conditions	Remarks
Consumption current (3)	I _{DD3}	—	32	38.4	mA	f _{CLK} = 36 MHz	ADCIN mode LoPwr = low
Consumption current (4)	I _{DD4}	—	22	27.5	mA	f _{CLK} = 25 MHz	ADCIN mode LoPwr = high
Timing specifications (14)	t _{ADC1}	—	(6)	—	ns		Refer to table 9
Timing specifications (15)	t _{ADC2}	Typ × 0.85	1/2f _{ADCLK}	Typ × 1.15	ns		
Timing specifications (16)	t _{ADC3}	Typ × 0.85	1/2f _{ADCLK}	Typ × 1.15	ns		
Timing specifications (17)	t _{AHLD4}	—	(14.5)	—	ns	C _L = 10 pF	
Timing specifications (18)	t _{AOD5}	—	(23.5)	—	ns	C _L = 10 pF	
Input current at ADC input	I _{IN_{CIN}}	-110	—	110	μA	V _{IN} = 1.0 to 2.0 V	
Clamp level at ADC input	OF2	—	(512)	—	LSB		
PGA gain at ADC input	GSL(0)	0.45	0.57	0.72	Times		
	GSL(63)	1.36	1.71	2.16	Times		
	GSL(127)	2.27	2.86	3.60	Times		
	GSL(191)	3.18	4.00	5.04	Times		
	GSL(255)	4.08	5.14	6.47	Times		

Note : Values within parentheses () are for reference.

Serial Interface Specifications

Timing Specifications

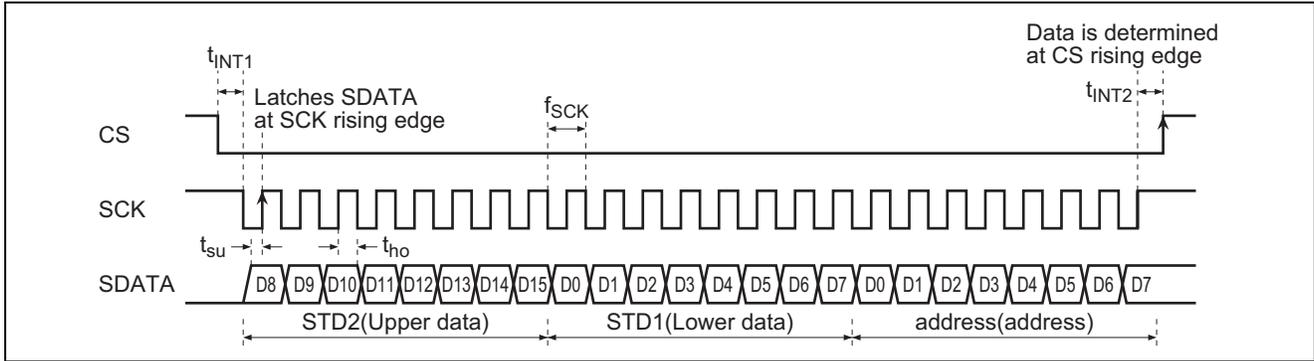


Figure 8 Serial Interface Timing Specifications

Item	Min	Max
f_{SCK}	—	5 MHz
$t_{INT1,2}$	50 ns	—
t_{su}	50 ns	—
t_{ho}	50 ns	—

- Notes:
1. 3 byte continuous communications.
 2. Input SCK with 24 clock when CS is Low.
 3. It becomes invalid when data communications are stopped on the way.
 4. Data becomes a default with hardware reset.
 5. Input more than double frequency of SCK to the CLK_in when transfer the serial data.

The Kind of Data

Data address has 256 type. H'00 to H'FF

H'00
⋮
H'EF

Data at timing generator part

H'F0
⋮
H'FF

Data at CDS part

Address map of each data referred to other sheet.

Details of timing generator refer to the timing chart on the other sheet together with this specification.

This specification only explains about the data of CDS part.

- Output mode (D2 to D4 of address H'F1 and address H'F4 of D6)
It is a test mode. Combination details are table 3 to 5. Normally set to all 0.
- SHA-fsel (D8 to D9 of address H'F1)
It is a LPF switching of SH amplifier. Frequency characteristics are referred to page 8. To get rough idea, set the double cut off frequency point with using.
- SHSW-fsel (D10 to D13 of address H'F1)
It is a time constant which sampling the black level of SH amplifier. Frequency characteristics are referred to page 8. To get rough idea, set the double cut off frequency point with using. S/N changes by this data, so find the appropriate point with set data to up/down.
- Test_I2 (D14 to D15 of address H'F1)
Current of ADC analog part can be set minutely. Normally use data = 0.
0: Default (100%)
1: 150%
2: 50%
3: 80%

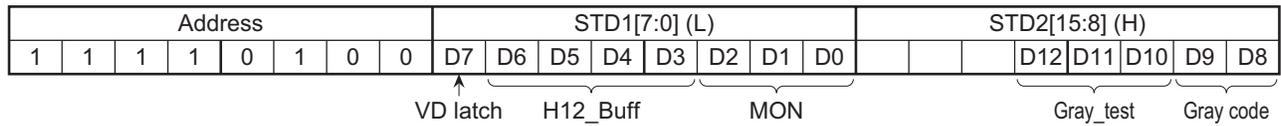
Address								STD1[7:0] (L)					STD2[15:8] (H)										
1	1	1	1	0	0	1	0				D4	D3	D2	D1	D0	D15	D14	D13	D12	D11	D10	D9	D8
								Clamp level					↑ Reset	↑ AD_sel	↑ CDS_buff	↑ Low_pwr	HGain-Nsel			↑ HGstop-Hsel			

- Clamp (D0 to D4 of address H'F2)
Determine the OB part level with digital code of ADC output.
Clamp level = setting data × 2 + 14
Default data is 9 = 32 LSB.
- HGstop-Hsel, HGain-Nsel (D8 to D11 of address H'F2)
Determine the lead-in speed of OB clamp. Details are referred to page 7. PGA gain need to be changed for switch the high speed leading mode. Transfer the gain +1/-1 to previous field, its switch to high speed leading mode.
- Low_PWR (D12 of address H'F2)
Switch circuit current and frequency characteristic.
Data = 0: 36 MHz guarantee
Data = 1: 25 MHz guarantee
- ADSEL (D14 of address H'F2)
Data = 0: Select CDS_in
Data = 1: Select ADC_in
- Reset (D15 of address H'F2)
Software reset.
Data = 1: Normal
Data = 0: Reset

Offset calibration should be done when starting up with using this bit. Details are referred to page 23.

Address								STD1[7:0] (L)							STD2[15:8] (H)								
1	1	1	1	0	0	1	1	D7	D6	D5	D4	D3	D2	D1	D0	D15	D14	D13	D12	D11	D10	D9	D8

- Address H'F3 are all testing data.
Normally set to all 0., or do not transfer the data.



- MON (D0 to D2 of address H’F4)
 Select the pulse which output to pin MON (pin 60).
 When D0 to D2: 0, Fix to Low When 1, ADCLK
 When 2, SP1 When 3, SP2
 When 4, OBP When 5, PBLK
 When 6, CPDM When 7, DLL_test

- H12Baff (D3 to D6 of address H’F4)
 Select the buffer size which output to pin H1A, H2A (pin 22, 26).
 D3: 2 mA buffer
 D4: 4 mA buffer
 D5: 10 mA buffer
 D6: 14 mA buffer

Above data can be on/off individually. Default is D6 can be on only. (18 mA buffer)

- VD latch (D7 of address H’F4)
 Data = 0: Gain data is determined when CS rising
 Data = 1: Gain data is determined when VD falling

Differential Code and Gray Code (D8 to D12 of address H’F4)

- Gray code (D8 to D9 of address H’F4)
 DC output code can be change to following type.

Gray Code [1]	Gray Code [0]	Output Code
0	0	Binary code
0	1	Gray code
1	0	Differential encoded binary
1	1	Differential encoded gray

- Serial data setting items (D10 to D12 of address H’F4)

Setting Bit	Setting Contents
Gray_test[0]	Standard data output timing control signal
Gray_test[1]	(Refer to the following table)
Gray_test[2]	ADCLK polar with OBP. (Lo→Positive edge, HI→Negative edge)

- Standard data output timing

Gray_test[1]	Gray_test[0]	Standard Data Output Timing
Low	Low	Third and fourth
Low	High	Fourth and fifth
High	Low	Fifth and sixth
High	High	Sixth and seventh

Ripple (pseudo outline made by quantized error) occurs on the point which swithing the ADC output multiple bit in parallel. When switching the several of ADC output at the same time, ripple (pseudo outline caused by miss quantization) occurs to the image.

Differential code and gray code are recommended for this countermeasure.

Figure 10 indicates circuit block. When luminance signal changes are smoothly, the number of bit of switching digital output bit can be reduced and easily to reduce the ripple using this function.

This function is especially effective for longer the settings of sensor more than $clk = 30\text{ kHz}$, and ADC output.

Figure 11 indicates the timing specifications.

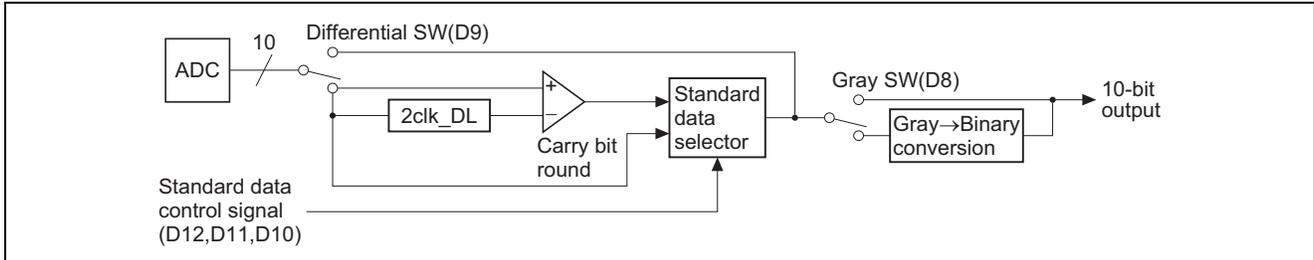


Figure 10 Differential Code, Gray Code Circuit

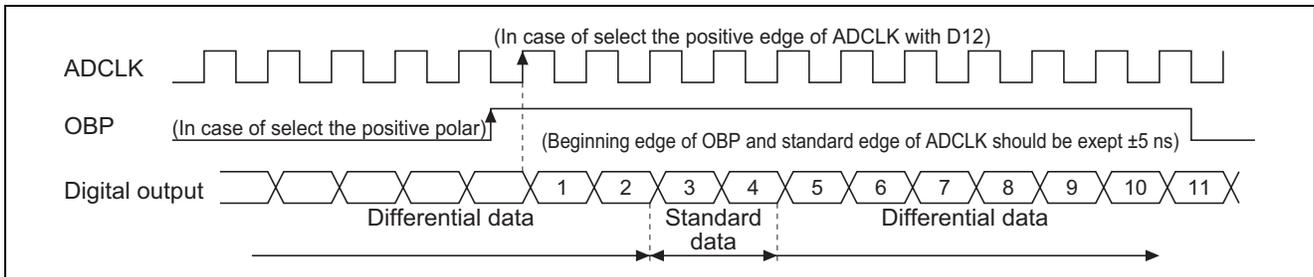


Figure 11 Differential Code Timing Specifications

To use differential code, complex circuit is necessary at DSP side.

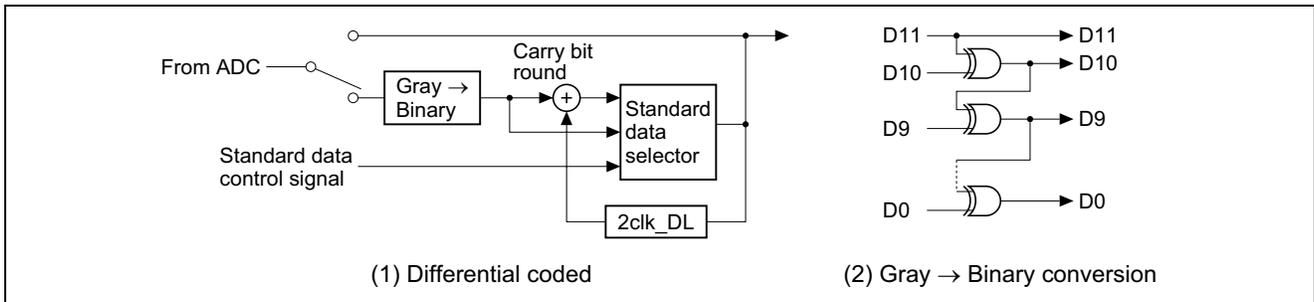
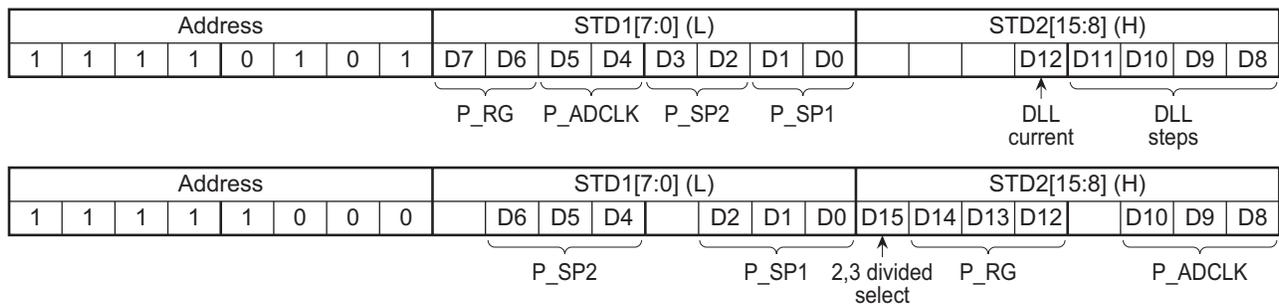


Figure 12 Complex Circuit Example



- Address H’F5 sets the DLL delay time and selects the 1/4 phase. Details are on the next page. And D15 of address H’F8 can switch 2/3 divided mode but ensure that this address data relative to valid/invalid.

	D15 of address H’F8 = 0	D15 of address H’F8 = 1
Divided mode	2 divided, 1/4 phase select	3 divided, 1/6 phase select
D0 to D7 of address H’F5	Valid	Invalid
D0 to D14 of address H’F8	Invalid	Valid

- Phase settings of high speed pulse (address H’F5 to H’F8)
 - Select the 1/4 phase from figure 13 at 2 divided mode (D15 = 0 of address H’F8).
 Select the 1/6 phase from figure 14 at 3 divided mode (D15 = 1 of address H’F8).
P_SP1, P_SP2, P_ADCLK, P_RG
 - Then select the necessary delay time from figure 15.
DL_SP1, DL_SP2, DL_RG, DL_ADCLK
 RG can be set both of rising / falling edge optionally.

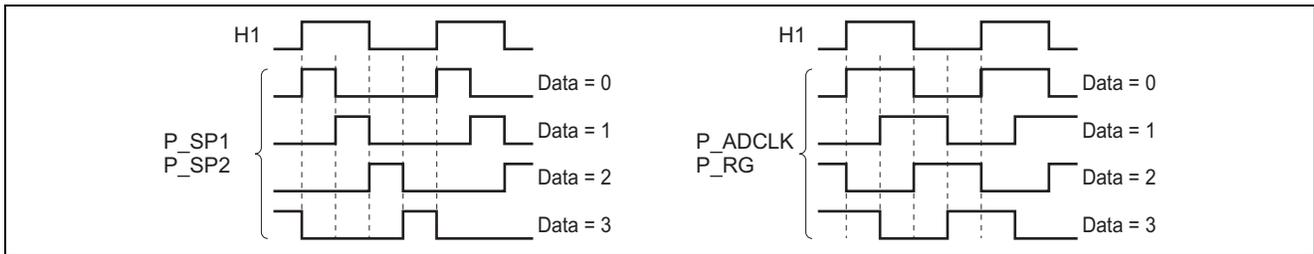


Figure 13 2 Divided Mode, 1/4 Phase Select (Valid at D15 = 0 of address H’F8)

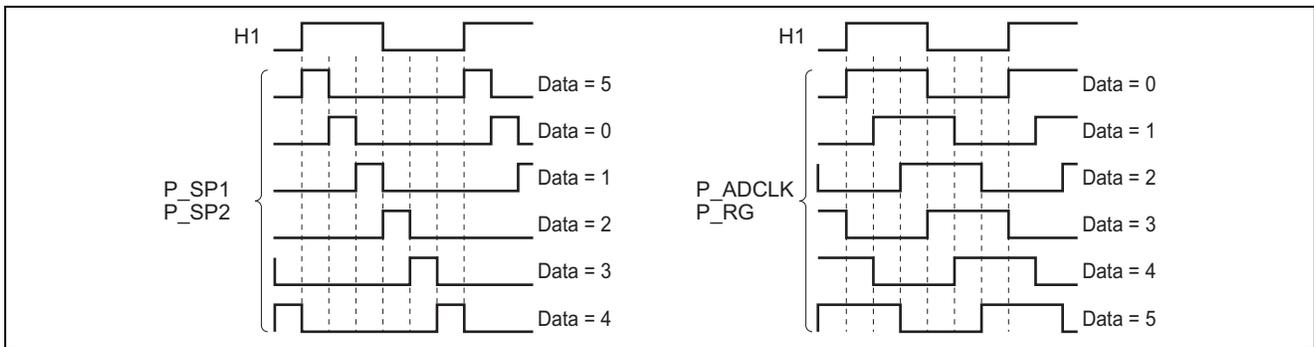


Figure 14 3 Divided Mode, 1/6 Phase Select (Valid at D15 = 1 of address H’F8)

Default Value of Each Phases

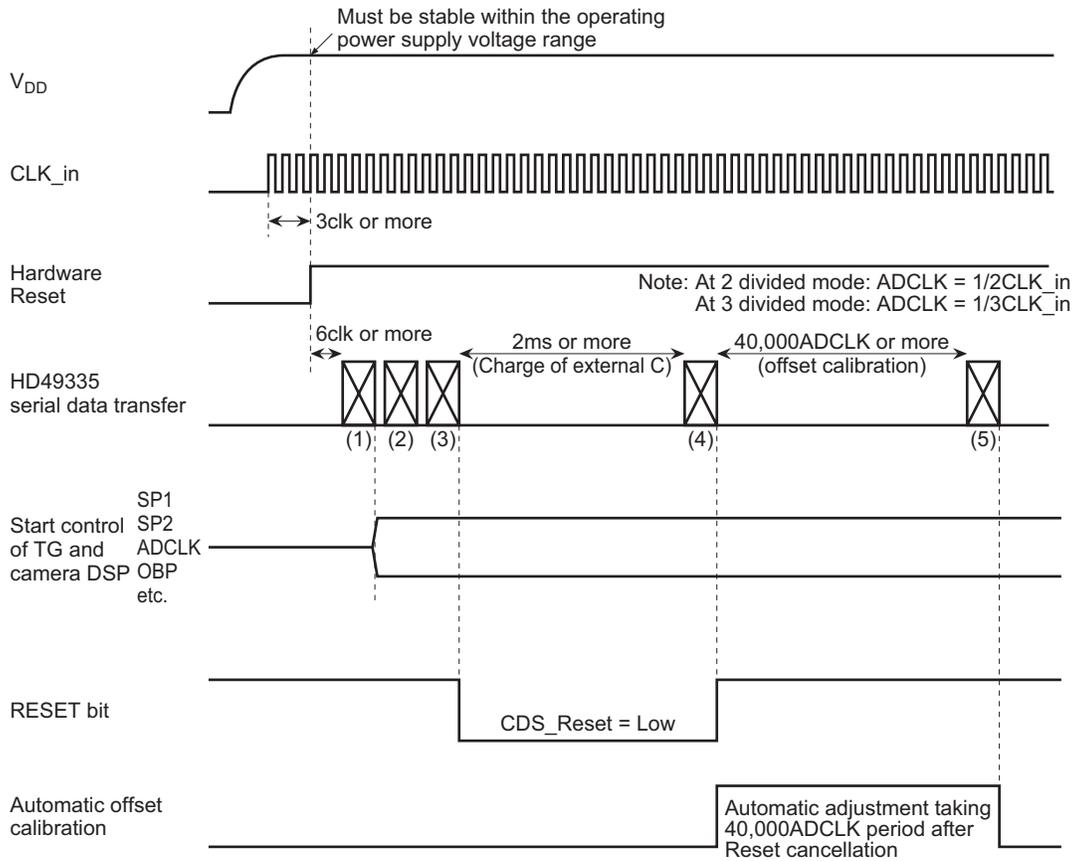
	P_SP1	P_SP2	P_ADCLK	P_RG
2 divided mode	1	2	1	0
3 divided mode	0	3	1	5

Note: 50% of duty pulse makes tr, tf of RG by DLL.

Address								STD1[7:0] (L)								STD2[15:8] (H)							
1	1	1	1	0	1	1	0	D7	D6	D5	D4	D3	D2	D1	D0				D12	D11	D10	D9	D8
								DL_SP2				DL_SP1				CDS_test	DL_ADCLK						

Address								STD1[7:0] (L)								STD2[15:8] (H)							
1	1	1	1	0	1	1	1	D7	D6	D5	D4	D3	D2	D1	D0				D12	D11	D10	D9	D8
								DL_RG_f				DL_RG_r				Dummy clamp th		Dummy clamp current					

Operation Sequence at Power On



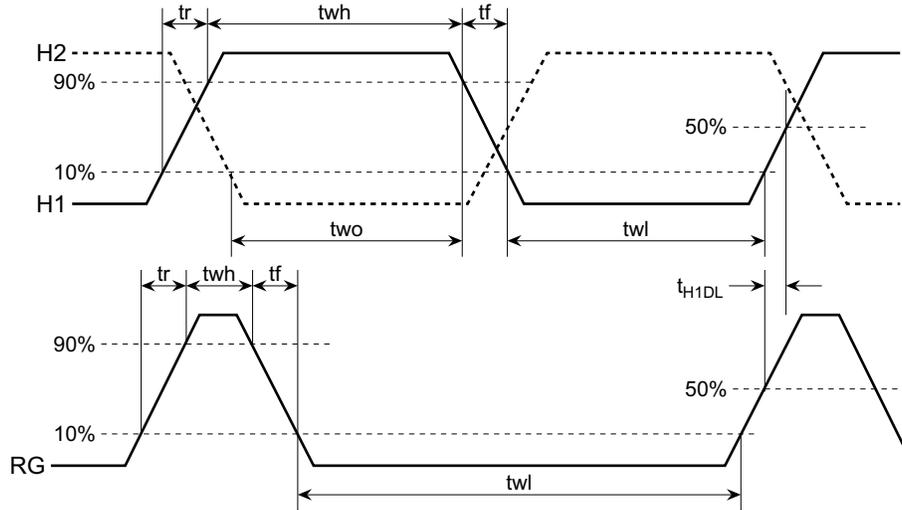
The following describes the above serial data transfer. For details of resistor settings are referred to serial data function table.

- (1) Resistor transfer of TG part : Wait more than 6clk after release the hardware Reset and then transfer the necessary data to TG part.
- (2) DLL data transfer of CDS part : Transfer the phase data of RG, SP1, SP2, ADCLK of CDS part.
- (3) Reset=L of CDS part : Transfer Reset bit = 0 of address H'F2.
- (4) Reset=H of CDS part : Transfer Reset bit = 1 of address H'F2. (Reset release)
- (5) Other data of CDS part : Transfer the SH_SW_fsel and other PGA.

* Before transfer the Reset bit = 0, TG series pulse need to be settled, so address H'00 to H'EF of TG part and H'F4 to H7F7 of CDS part should transfer in advance.

Timing Specifications of High Speed Pulse

• H1, H2, RG waveform



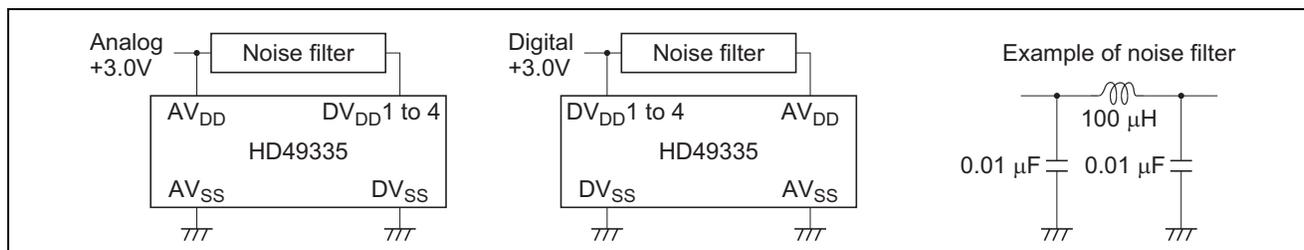
Item	twh			twl			tr			tf			Unit	Load capacitance
	min	typ	max											
H1/H2	14	20	—	14	20	—	—	8.0	14	—	8.0	14	ns	165 pF
RG	7	10	—	—	37	—	—	4.0	—	—	4.0	—	ns	15 pF
XV1 to 4	—	—	—	—	—	—	—	20	—	—	20	—	ns	15 pF
CH1 to 4	—	—	—	—	—	—	—	20	—	—	20	—	ns	15 pF
XSUB/SUB_SW	—	—	—	—	—	—	—	20	—	—	20	—	ns	15 pF

Item	two			Unit
	min	typ	max	
H1/H2 overlap	12	20	—	ns

Power supply specification of H1, H2, RG are 3.0 V to 3.3 V.
Values are sensor CLK = when 18 MHz.

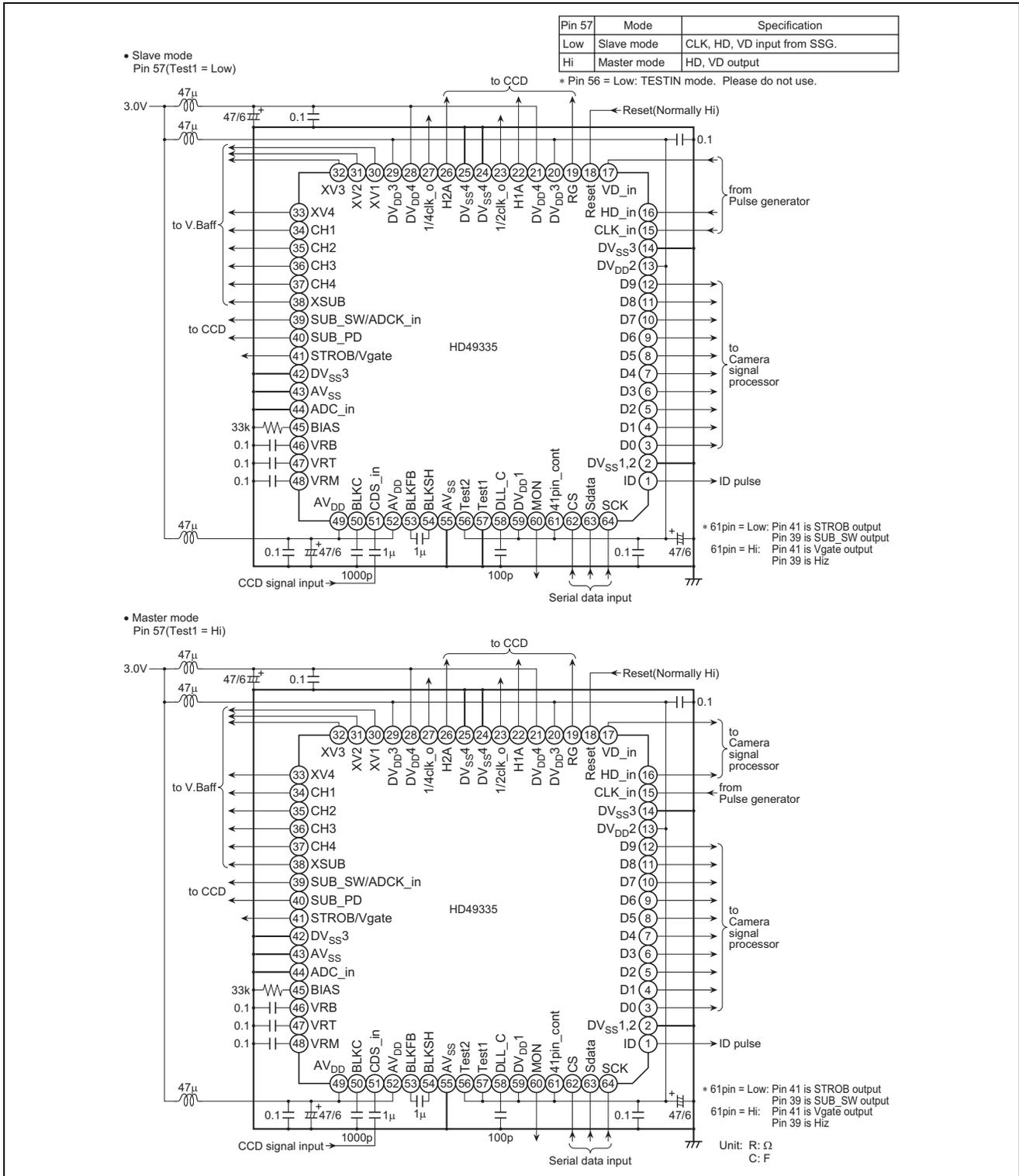
Notice for Use

- Careful handling is necessary to prevent damage due to static electricity.
- This product has been developed for consumer applications, and should not be used in non-consumer applications.
- As this IC is sensitive to power line noise, the ground impedance should be kept as small as possible. Also, to prevent latchup, a ceramic capacitor of 0.1 μF or more and an electrolytic capacitor of 10 μF or more should be inserted between the ground and power supply.
- Common connection of AV_{DD} and DV_{DD} should be made off-chip. If AV_{DD} and DV_{DD} are isolated by a noise filter, the phase difference should be 0.3 V or less at power-on and 0.1 V or less during operation.
- If a noise filter is necessary, make a common connection after passage through the filter, as shown in the figure below.

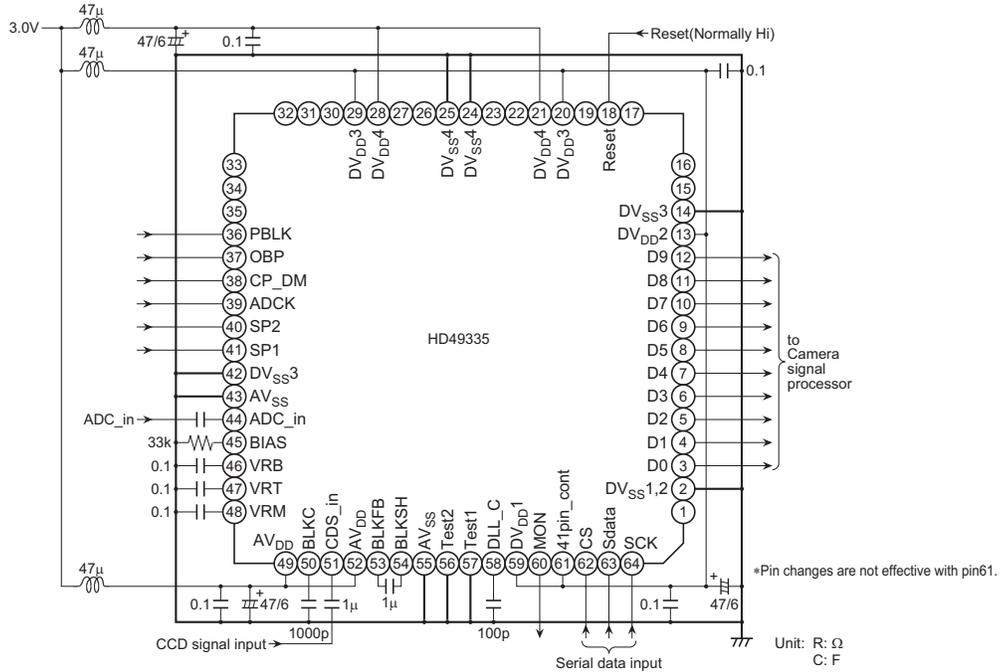


- Connect AV_{SS} and DV_{SS} off-chip using a common ground. If there are separate analog system and digital system set grounds, connect to the analog system.
- When V_{DD} is specified in the data sheet, this indicates AV_{DD} and DV_{DD} .
- No Connection (NC) pins are not connected inside the IC, but it is recommended that they be connected to power supply or ground pins or left open to prevent crosstalk in adjacent analog pins.
- To ensure low thermal resistance of the package, a Cu-type lead material is used. As this material is less tolerant of bending than Fe-type lead material, careful handling is necessary.
- The infrared reflow soldering method should be used to mount the chip. Note that general heating methods such as solder dipping cannot be used.
- Serial communication should not be performed during the effective video period, since this will result in degraded picture quality. Also, use of dedicated ports is recommended for the SCK and SDATA signals used in the HD49330AF. If ports are to be shared with another IC, picture quality should first be thoroughly checked.
- At power-on, automatic adjustment of the offset voltage generated from PGA, ADC, etc., must be implemented in accordance with the power-on operating sequence (see page 24).
- Ripple noise of DC/DC converter which generates the voltage of analog part should set under -50 dB with power supply voltage.

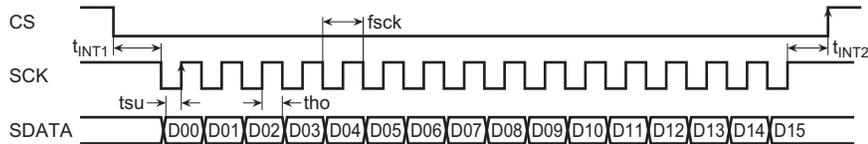
Example of Recommended External Circuit



- CDS single operating mode
Pin 56(Test2 = Low) *Pin 57 is "Don't care" in this mode.



Serial data when CDS single operation mode are following register specifications.
(Latch timing specification is same as normal mode)



	Register 0	Register 1	Register 2	Register 3	Register 4	Register 5	Register 6	Register 7
D00	Low	0	High	1	Low	0	High	1
D01	Low	0	Low	0	High	1	High	1
D02	Low	0	Low	0	Low	0	High	1
D03	X	0 SLP	Low: Normal High: Sleep	0 Clamp(0)	1	0 MON(0)	0 P_SP1(0)	1 DL_SP1(0)
D04	X	0 STBY	Low: Normal High: Standby	0 Clamp(1)	0	0 MON(1)	0 P_SP1(1)	0 DL_SP1(1)
D05	PGA(0) LSB	0	Output mode(LINV)	0 Clamp(2)	0	0 MON(2)	0 P_SP2(0)	1 DL_SP1(2)
D06	PGA(1)	0	Output mode(MINV)	0 Clamp(3)	1	0 H12Baff(0)	0 P_SP2(1)	1 DL_SP1(3)
D07	PGA(2)	0	Output mode(Test0)	0 Clamp(4)	0	0 H12Baff(1)	0 P_ADCLK(0)	1 DL_SP2(0)
D08	PGA(3)	0	SHA-fsel(0)	0 HGstop-Hsel(0)	0	0 H12Baff(2)	0 P_ADCLK(1)	0 DL_SP2(1)
D09	PGA(4)	0	SHA-fsel(1)	0 HGstop-Hsel(1)	0	0 H12Baff(3)	1 P_RG(0)	0 DL_SP2(2)
D10	PGA(5)	0	SHSW-fsel(0)	0 HGain-Nsel(0)	0	0 VD latch	0 P_RG(1)	0 DL_SP2(3)
D11	PGA(6)	0	SHSW-fsel(1)	0 HGain-Nsel(1)	0	0 Gray1	0 DLL_CK(0)	1 DL_ADCLK(0)
D12	PGA(7) MSB	0	SHSW-fsel(2)	0 LoPwr	Low: Normal High: Low power	1	0 Gray2	0 DLL_CK(1)
D13	Test_I1 (0)	0	SHSW-fsel(3)	0	X	0	0 Gray_ts(0)	0 DLL_CK(2)
D14	Test_I1 (1)	0	Test_I2 (0)	0	ADSEL	Low: CDSin High: ADin	0	0 Gray_ts(1)
D15	Test_I1 (2)	1	Test_I2 (1)	0	Reset	Low: Reset High: Normal	1	0 Gray_ts(2)

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